

STREAM FOUNDATION

Tender Ref. No: STREAM/EQ/065/12/2025

Atomic Force Microscope (AFM)

CORRIGENDUM-1

DATE:31/01/2026

Sl No	Tender clause – ANNEXURE B	Original Clause	Revised clause
1	Sl.No.3	System Scanner specifications, our system XY Scanner resolution: 0.05 nm or better	System Scanner specifications, our system XY Scanner resolution will be 0.2 nm or better
2	Sl.No.5	Kelvin Probe Force Microscopy (KPFM) (Lift mode/ dual pass) Capable of capturing simultaneously Height, potential and work function channels individually in Real time	Kelvin Probe Force Microscopy (KPFM) (dual pass) Capable of capturing simultaneously Height, potential and work function channels individually in Real time
3	Sl.No.8.3	AFM calibration kit with necessary standard samples for all the above modes (included electrical modes like EFM, SKPM, CAFM, STM) should be provided	AFM calibration kit with necessary standard samples for all the above modes (included electrical modes like EFM, SKPM) should be provided